

17

light source, form a second image record from the second light source, and form a third image record from the third light source, wherein defects are located by comparing the first data record, the second data record, and the third data record.

53. A method for determining a defect record of an image plane comprising:

- obtaining a first image record based on light influenced by the image plane from a first light source;
- obtaining a second image record based on light influenced by the image plane from a second light source;
- obtaining a maximum pixel intensity record by comparing the first and second image records and selecting the highest pixel intensity value for a given pixel location;
- obtaining a minimum pixel intensity record by comparing the first and second image records and selecting the lowest pixel intensity value for a given pixel location;
- obtaining a difference record by subtracting the minimum pixel intensity record from the maximum pixel intensity value;
- locating the center of a defect region by locating localized minimums in the difference record; and
- determining defect boundaries based on the difference record.

54. The method of claim 53, further comprising:
determining upper and lower pixel intensity values from the difference record; and

18

labeling pixels as defective based on the upper and lower thresholds and the defect boundaries.

55. The system of claim 53, wherein the image plane comprises a document.

56. The system of claim 53, wherein the image plane comprises a platen.

57. The method of claim 53, further comprising:
correcting the image using the defect boundaries and difference record.

58. The method of claim 57, wherein the defect region is corrected by increasing an intensity of each first image record pixel in the defect region by an amount proportional to the intensity of each matching defect pixel.

59. A method for locating image defects comprising:
locating shadow pixels in a first image record;
locating shadow pixels in a second image record;
comparing the shadow pixel regions to form defect boundaries;
forming a defect map based on the defect boundaries; and
correcting the image using the defect map, wherein the first image record is corrected by increasing an intensity of each first image record pixel by an amount proportional to the intensity of each defect pixel.

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